

# 74ALVT16823

18-bit bus-interface D-type flip-flop with reset and enable;  
3-state

Rev. 6 — 20 October 2020

Product data sheet

## 1. General description

The 74ALVT16823 is an 18-bit positive-edge triggered D-type flip-flop with 3-state outputs, reset and enable.

The device can be used as two 9-bit flip-flops or one 18-bit flip-flop. The device features clock (nCP), clock enable (nCE), master reset (nMR) and output enable (nOE), inputs each controlling 9-bits. When nCE is LOW, the flip-flops will store the state of their individual D-inputs that meet the set-up and hold time requirements on the LOW-to-HIGH clock (nCP) transition. A HIGH on nOE causes the outputs to assume a high-impedance OFF-state. Operation of the nOE input does not affect the state of the flip-flops. A LOW on nMR will reset the flip-flops LOW. Bus hold data inputs eliminate the need for external pull-up resistors to define unused inputs

## 2. Features and benefits

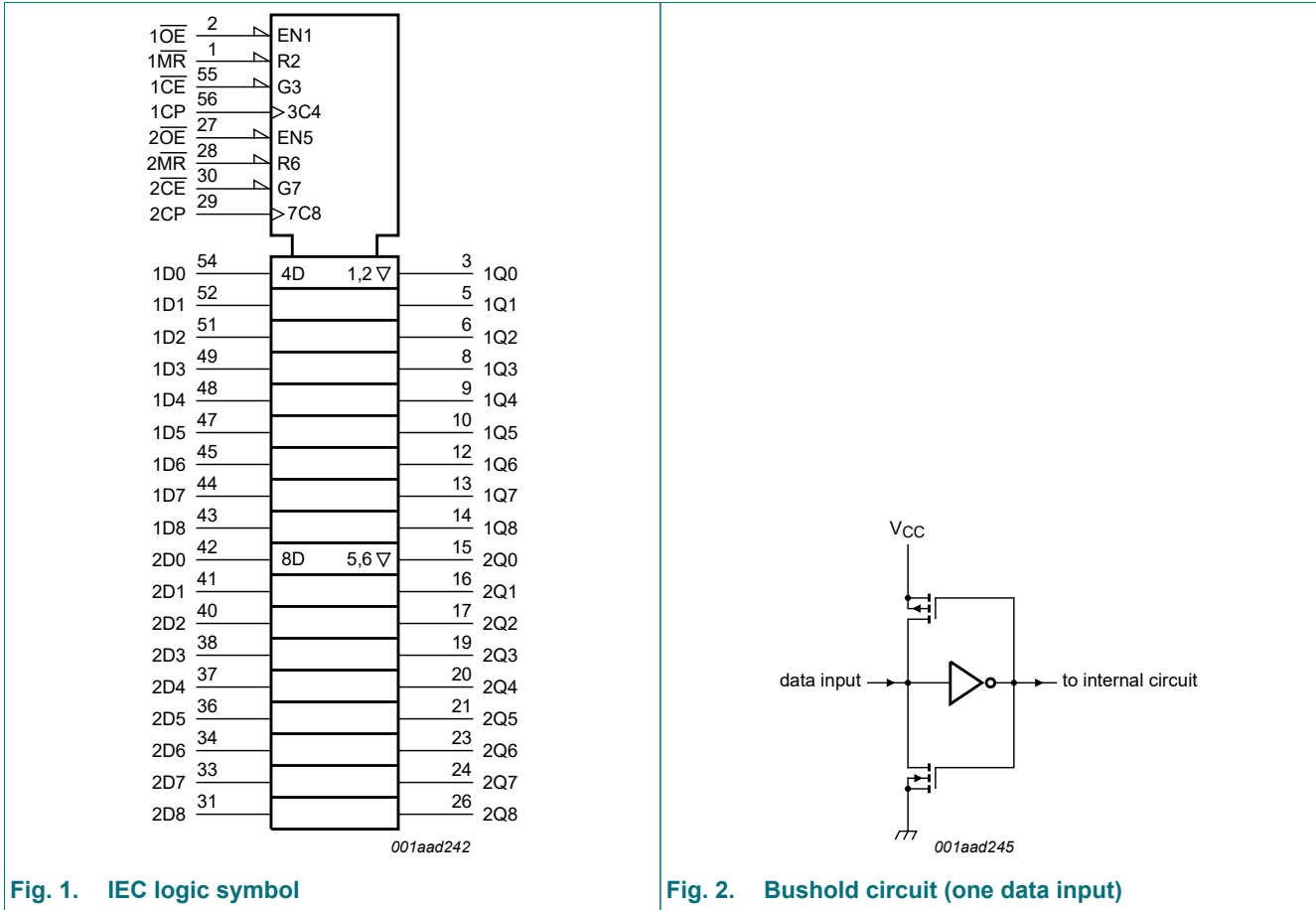
- Wide supply voltage range from 2.3 V to 3.6 V
- Overvoltage tolerant inputs to 5.5 V
- BiCMOS high speed and output drive
- Direct interface with TTL levels
- Bus hold on data inputs
- Power-up 3-state
- I<sub>OFF</sub> circuitry provides partial Power-down mode operation
- Two sets of high speed parallel registers with positive edge-triggered D-type flip-flops
- Ideal where high speed, light loading, or increased fan-in are required with MOS microprocessors
- Live insertion and extraction permitted
- Power-up reset
- No bus current loading when output is tied to 5 V bus
- Output capability: +64 mA to -32 mA
- Latch-up performance exceeds 500 mA per JESD 78 Class II Level B
- ESD protection:
  - MIL STD 883, method 3015: exceeds 2000 V
  - MM: exceeds 200 V
- Specified from -40 °C to 85 °C

## 3. Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
74ALVT16823DGG	-40 °C to +85 °C	TSSOP56	plastic thin shrink small outline package; 56 leads; body width 6.1 mm	SOT364-1

### 4. Functional diagram



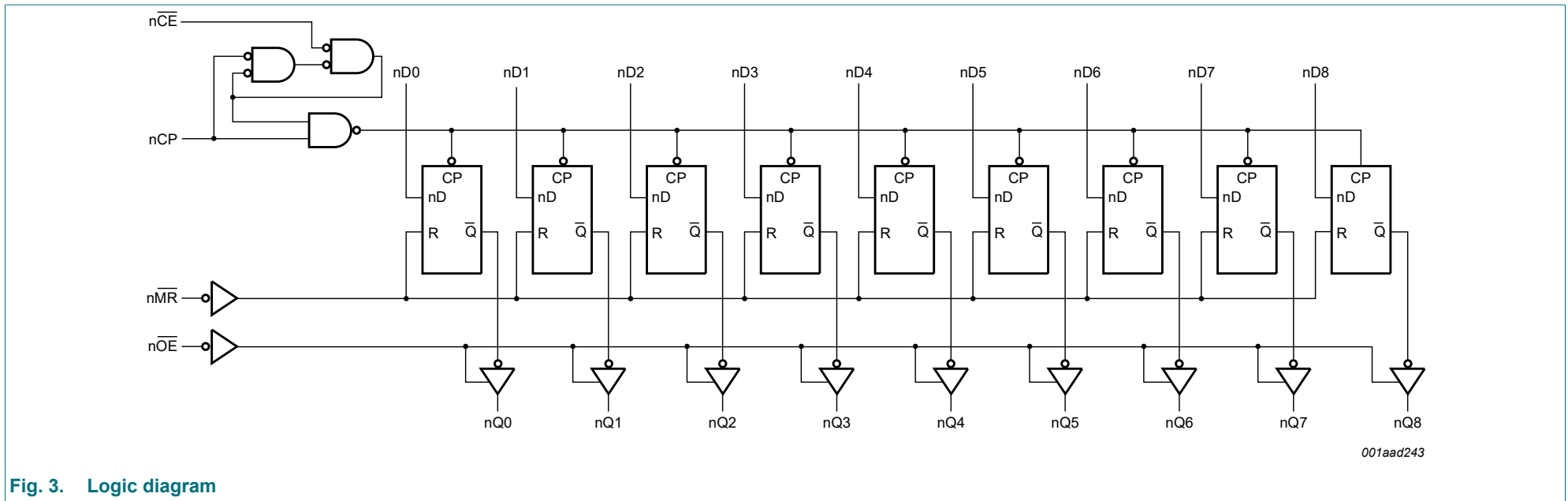


Fig. 3. Logic diagram

## 5. Pinning information

### 5.1. Pinning

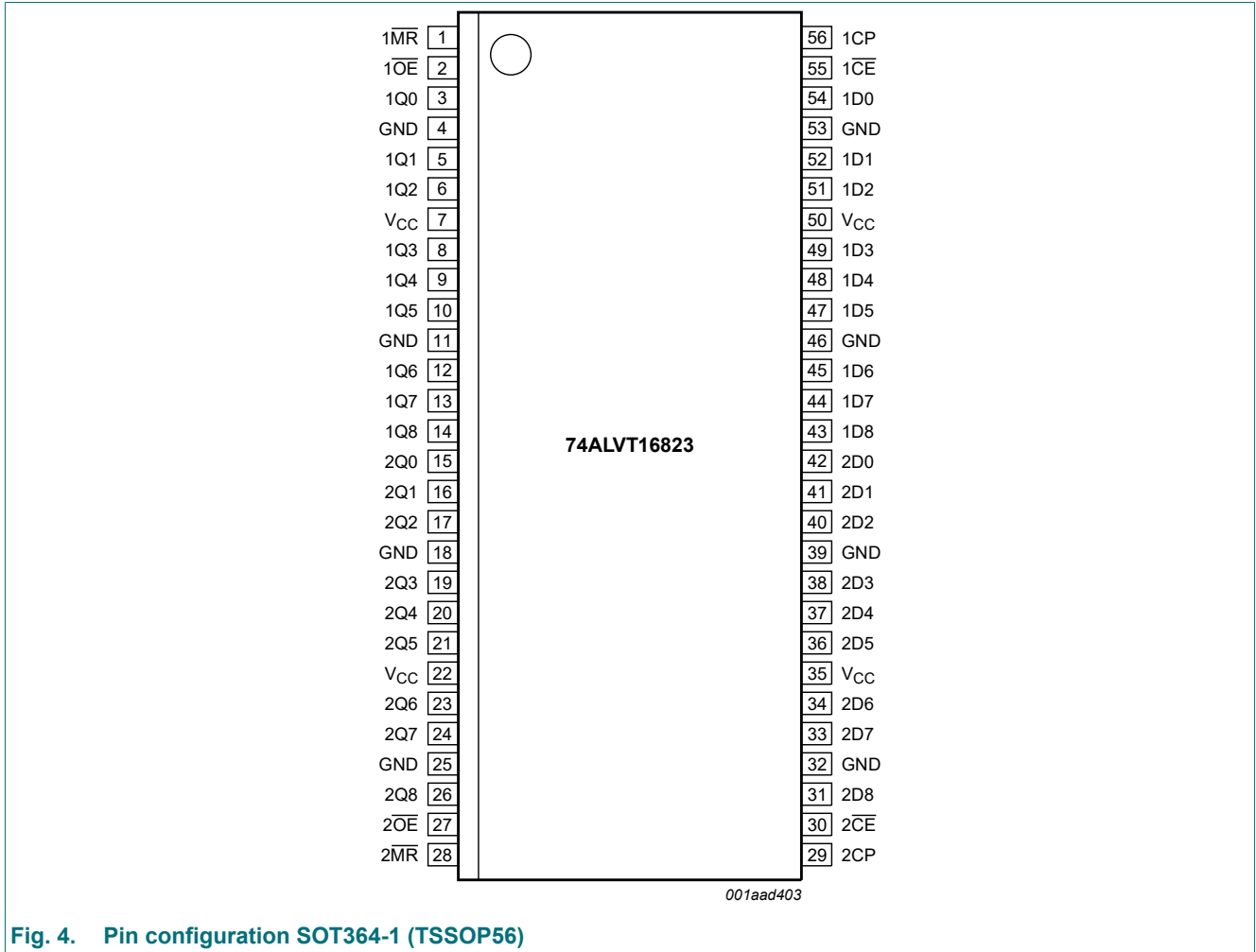


Fig. 4. Pin configuration SOT364-1 (TSSOP56)

### 5.2. Pin description

Table 2. Pin description

Symbol	Pin	Description
1D0, 1D1, 1D2, 1D3, 1D4, 1D5, 1D6, 1D7, 1D8	54, 52, 51, 49, 48, 47, 45, 44, 43	data inputs
1Q0, 1Q1, 1Q2, 1Q3, 1Q4, 1Q5, 1Q6, 1Q7, 1Q8	3, 5, 6, 8, 9, 10, 12, 13, 14	data outputs
2D0, 2D1, 2D2, 2D3, 2D4, 2D5, 2D6, 2D7, 2D8	42, 41, 40, 38, 37, 36, 34, 33, 31	data inputs
2Q0, 2Q1, 2Q2, 2Q3, 2Q4, 2Q5, 2Q6, 2Q7, 2Q8	15, 16, 17, 19, 20, 21, 23, 24, 26	data outputs
1MR, 2MR	1, 28	master reset input (active-LOW)
1OE, 2OE	2, 27	output enable inputs (active LOW)
1CP, 2CP	56, 29	clock pulse inputs (active rising edge)
1CE, 2CE	55, 30	clock enable input (active-LOW)
GND	4, 11, 18, 25, 32, 39, 46, 53	ground (0 V)
V <sub>CC</sub>	7, 22, 35, 50	supply voltage

## 6. Functional description

**Table 3. Function table**

*H = HIGH voltage level; h = HIGH voltage level one set-up time prior to the LOW-to-HIGH clock transition;*

*L = LOW voltage level; l = LOW voltage level one set-up time prior to the LOW-to-HIGH clock transition;*

*NC = no change; X = don't care; Z = high-impedance OFF-state;*

*↑ = LOW-to-HIGH clock transition;  $\bar{\uparrow}$  = not a LOW-to-HIGH clock transition.*

Operating mode	Input					Output
	nOE	nMR	nCE	nCP	nDn	nQn
clear	L	L	X	X	X	L
load and read data	L	H	L	↑	h	H
					l	L
hold	L	H	H	$\bar{\uparrow}$	X	NC
high-impedance	H	X	X	X	X	Z

## 7. Limiting values

**Table 4. Limiting values**

*In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).*

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		-0.5	+4.6	V
V <sub>I</sub>	input voltage		[1] -0.5	+7.0	V
V <sub>O</sub>	output voltage	output in OFF-state or HIGH-state	[1] -0.5	+7.0	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-	-50	mA
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-	-50	mA
I <sub>O</sub>	output current	output in LOW-state	-	128	mA
		output in HIGH-state	-64	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
T <sub>j</sub>	junction temperature		[2] -	150	°C

[1] The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

## 8. Recommended operating conditions

**Table 5. Recommended operating conditions**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>V<sub>CC</sub> = 2.5 V</b>						
V <sub>CC</sub>	supply voltage		2.3	-	2.7	V
V <sub>I</sub>	input voltage		0	-	5.5	V
I <sub>OH</sub>	HIGH-level output current		-	-	-8	mA
I <sub>OL</sub>	LOW-level output current	none	-	-	8	mA
		current duty cycle ≤ 50 %; f ≥ 1 kHz	-	-	24	mA
Δt/Δv	input transition rise or fall rate	outputs enabled	-	-	10	ns/V
T <sub>amb</sub>	ambient temperature	in free air	-40	-	+85	°C

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>V<sub>CC</sub> = 3.3 V</b>						
V <sub>CC</sub>	supply voltage		3.0	-	3.6	V
V <sub>I</sub>	input voltage		0	-	5.5	V
I <sub>OH</sub>	HIGH-level output current		-	-	-32	mA
I <sub>OL</sub>	LOW-level output current	none	-	-	32	mA
		current duty cycle ≤ 50 %; f ≥ 1 kHz	-	-	64	mA
Δt/Δv	input transition rise or fall rate	outputs enabled	-	-	10	ns/V
T <sub>amb</sub>	ambient temperature	in free air	-40	-	+85	°C

## 9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
<b>V<sub>CC</sub> = 2.5 V ± 0.2 V</b>						
V <sub>IK</sub>	input clamping voltage	V <sub>CC</sub> = 2.3 V; I <sub>IK</sub> = -18 mA	-	-0.85	-1.2	V
V <sub>IH</sub>	HIGH-level input voltage		1.7	-	-	V
V <sub>IL</sub>	LOW-level input voltage		-	-	0.7	V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>CC</sub> = 2.3 V to 2.7 V; I <sub>O</sub> = -100 μA	V <sub>CC</sub> - 0.2	V <sub>CC</sub>	-	V
		V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = -8 mA	1.8	2.5	-	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = 100 μA	-	0.07	0.2	V
		V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = 24 mA	-	0.3	0.5	V
		V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = 8 mA	-	-	0.4	V
V <sub>OL(pu)</sub>	power-up LOW-level output voltage	V <sub>CC</sub> = 2.7 V; I <sub>O</sub> = 1 mA; V <sub>I</sub> = V <sub>CC</sub> or GND [2]	-	-	0.55	V
I <sub>I</sub>	input leakage current	control pins				
		V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = V <sub>CC</sub> or GND	-	0.1	±1	μA
		V <sub>CC</sub> = 0 V to 2.7 V; V <sub>I</sub> = 5.5 V	-	0.1	10	μA
		I/O data pins [3]				
		V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = V <sub>CC</sub>	-	0.1	1	μA
		V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = 0 V	-	+0.1	-5	μA
I <sub>OFF</sub>	power-off leakage current	V <sub>CC</sub> = 0 V; V <sub>I</sub> or V <sub>O</sub> = 0 V to 4.5 V	-	+0.1	±100	μA
I <sub>BHL</sub>	bus hold LOW current	data inputs; V <sub>CC</sub> = 2.3 V; V <sub>I</sub> = 0.7 V [4]	-	100	-	μA
I <sub>BHH</sub>	bus hold HIGH current	data inputs; V <sub>CC</sub> = 2.3 V; V <sub>I</sub> = 1.7 V [4]	-	-70	-	μA
I <sub>EX</sub>	external current	output HIGH-state when V <sub>O</sub> > V <sub>CC</sub> ; V <sub>O</sub> = 5.5 V; V <sub>CC</sub> = 2.3 V	-	10	125	μA
I <sub>O(pu pd)</sub>	power-up/power-down output current	V <sub>CC</sub> ≤ 1.2 V; V <sub>O</sub> = 0.5 V to V <sub>CC</sub> ; V <sub>I</sub> = GND or V <sub>CC</sub> [5]	-	1	±100	μA
I <sub>OZ</sub>	OFF-state output current	V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = V <sub>IL</sub> or V <sub>IH</sub>				
		output HIGH state; V <sub>O</sub> = 2.3 V	-	0.5	5	μA
		output LOW-state; V <sub>O</sub> = 0.5 V	-	+0.5	-5	μA

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
I <sub>CC</sub>	supply current	V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = GND or V <sub>CC</sub> ; I <sub>O</sub> = 0 A				
		outputs HIGH-state	-	0.04	0.1	mA
		outputs LOW-state	-	2.7	4.5	mA
		outputs disabled [6]	-	0.04	0.1	mA
ΔI <sub>CC</sub>	additional supply current	per input pin; V <sub>CC</sub> = 2.3 V to 2.7 V; one input at V <sub>CC</sub> - 0.6 V, other inputs at V <sub>CC</sub> or GND [7]	-	0.04	0.4	mA
C <sub>I</sub>	input capacitance	V <sub>I</sub> = 0 V or V <sub>CC</sub>	-	3	-	pF
C <sub>O</sub>	output capacitance	V <sub>IO</sub> = 0 V or 3.0 V	-	9	-	pF
<b>V<sub>CC</sub> = 3.3 V ± 0.3 V</b>						
V <sub>IK</sub>	input clamping voltage	V <sub>CC</sub> = 3.0 V; I <sub>IK</sub> = -18 mA	-	-0.85	-1.2	V
V <sub>IH</sub>	HIGH-level input voltage		2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage		-	-	0.8	V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>CC</sub> = 3.0 V to 3.6 V; I <sub>O</sub> = -100 μA	V <sub>CC</sub> - 0.2	V <sub>CC</sub>	-	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = -32 mA	2.0	2.3	-	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 100 μA	-	0.07	0.2	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 16 mA	-	0.25	0.4	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 32 mA	-	0.3	0.5	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 64 mA	-	0.4	0.55	V
V <sub>OL(pu)</sub>	power-up LOW-level output voltage	V <sub>CC</sub> = 3.6 V; I <sub>O</sub> = 1 mA; V <sub>I</sub> = V <sub>CC</sub> or GND [2]	-	-	0.55	V
I <sub>I</sub>	input leakage current	control pins				
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>CC</sub> or GND	-	0.1	±1	μA
		V <sub>CC</sub> = 0 V or 3.6 V; V <sub>I</sub> = 5.5 V	-	0.1	10	μA
		I/O data pins [3]				
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>CC</sub>	-	0.5	1	μA
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V	-	+0.1	-5	μA
I <sub>OFF</sub>	power-off leakage current	V <sub>CC</sub> = 0 V; V <sub>I</sub> or V <sub>O</sub> = 0 V to 4.5 V	-	0.1	±100	μA
I <sub>BHL</sub>	bus hold LOW current	data inputs; V <sub>CC</sub> = 3 V; V <sub>I</sub> = 0.8 V	75	130	-	μA
I <sub>BHH</sub>	bus hold HIGH current	data inputs; V <sub>CC</sub> = 3 V; V <sub>I</sub> = 2.0 V	-75	-140	-	μA
I <sub>BHLO</sub>	bus hold LOW overdrive current	data inputs; V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V to 3.6 V [8]	500	-	-	μA
I <sub>BHHO</sub>	bus hold HIGH overdrive current	data inputs; V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V to 3.6 V [8]	-500	-	-	μA
I <sub>EX</sub>	external current	output HIGH-state when V <sub>O</sub> > V <sub>CC</sub> ; V <sub>O</sub> = 5.5 V; V <sub>CC</sub> = 3.0 V	-	10	125	μA
I <sub>O(pu/pd)</sub>	power-up/power-down output current	V <sub>CC</sub> ≤ 1.2 V; V <sub>O</sub> = 0.5 V to V <sub>CC</sub> ; V <sub>I</sub> = GND or V <sub>CC</sub> [9]	-	1	±100	μA
I <sub>OZ</sub>	OFF-state output current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>IL</sub> or V <sub>IH</sub>				
		output HIGH state; V <sub>O</sub> = 3.0 V	-	0.5	5	μA
		output LOW-state; V <sub>O</sub> = 0.5 V	-	+0.5	-5	μA

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
I <sub>CC</sub>	supply current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = GND or V <sub>CC</sub> ; I <sub>O</sub> = 0 A				
		outputs HIGH-state	-	0.06	0.1	mA
		outputs LOW-state	-	3.9	5.5	mA
		outputs disabled [6]	-	0.06	0.1	mA
ΔI <sub>CC</sub>	additional supply current	per input pin; V <sub>CC</sub> = 3 V to 3.6 V; one input at V <sub>CC</sub> - 0.6 V, other inputs at V <sub>CC</sub> or GND [7]	-	0.04	0.4	mA
C <sub>I</sub>	input capacitance	V <sub>I</sub> = 0 V or V <sub>CC</sub>	-	3	-	pF
C <sub>O</sub>	output capacitance	V <sub>IO</sub> = 0 V or 3.0 V	-	9	-	pF

- [1] All typical values for V<sub>CC</sub> = 2.5 V ± 0.2 V are measured at V<sub>CC</sub> = 2.5 V and T<sub>amb</sub> = 25 °C.  
All typical values for V<sub>CC</sub> = 3.3 V ± 0.3 V are measured at V<sub>CC</sub> = 3.3 V and T<sub>amb</sub> = 25 °C.
- [2] For valid test results, data must not be loaded into the flip-flops after applying power.
- [3] Unused pins at V<sub>CC</sub> or GND.
- [4] Not guaranteed.
- [5] This parameter is valid for any V<sub>CC</sub> between 0 V and 1.2 V with a transition time of up to 10 ms.  
From V<sub>CC</sub> = 1.2 V to V<sub>CC</sub> = 2.5 V ± 0.2 V a transition time of 100 μs is permitted. This parameter is valid for T<sub>amb</sub> = 25 °C only.
- [6] I<sub>CC</sub> is measured with outputs pulled up to V<sub>CC</sub> or pulled down to ground.
- [7] This is the increase in supply current for each input at the specified voltage level other than V<sub>CC</sub> or GND.
- [8] This is the bus hold overdrive current required to force the input to the opposite logic state.
- [9] This parameter is valid for any V<sub>CC</sub> between 0 V and 1.2 V with a transition time of up to 10 ms.  
From V<sub>CC</sub> = 1.2 V to V<sub>CC</sub> = 3.3 V ± 0.3 V a transition time of 100 μs is permitted. This parameter is valid for T<sub>amb</sub> = 25 °C only.

## 10. Dynamic characteristics

**Table 7. Dynamic characteristics**

Voltages are referenced to GND (ground = 0 V); for test circuit see Fig. 9.

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
<b>V<sub>CC</sub> = 2.5 V ± 0.2 V</b>						
t <sub>PLH</sub>	LOW to HIGH propagation delay	nCP to nQn; see Fig. 5	1.5	2.9	4.5	ns
t <sub>PHL</sub>	HIGH-to-LOW propagation delay	nCP to nQn; see Fig. 5	1.4	2.7	4.2	ns
		nMR to nQn; see Fig. 7	1.5	2.7	4.2	ns
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	2.1	3.4	5.0	ns
t <sub>PZL</sub>	OFF-state to LOW propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	1.8	3.0	4.7	ns
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	1.7	3.0	4.3	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	1.4	2.3	3.3	ns
t <sub>su(H)</sub>	set-up time HIGH	nDn to nCP; see Fig. 6	1.0	0.5	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	1.0	0.2	-	ns
t <sub>su(L)</sub>	set-up time LOW	nDn to nCP; see Fig. 6	1.8	1.3	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	0.5	-0.1	-	ns
t <sub>h(H)</sub>	hold time HIGH	nDn to nCP; see Fig. 6	0.1	-1.4	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	1.0	0.2	-	ns
t <sub>h(L)</sub>	hold time LOW	nDn to nCP; see Fig. 6	0.1	-0.5	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	1.0	-0.1	-	ns

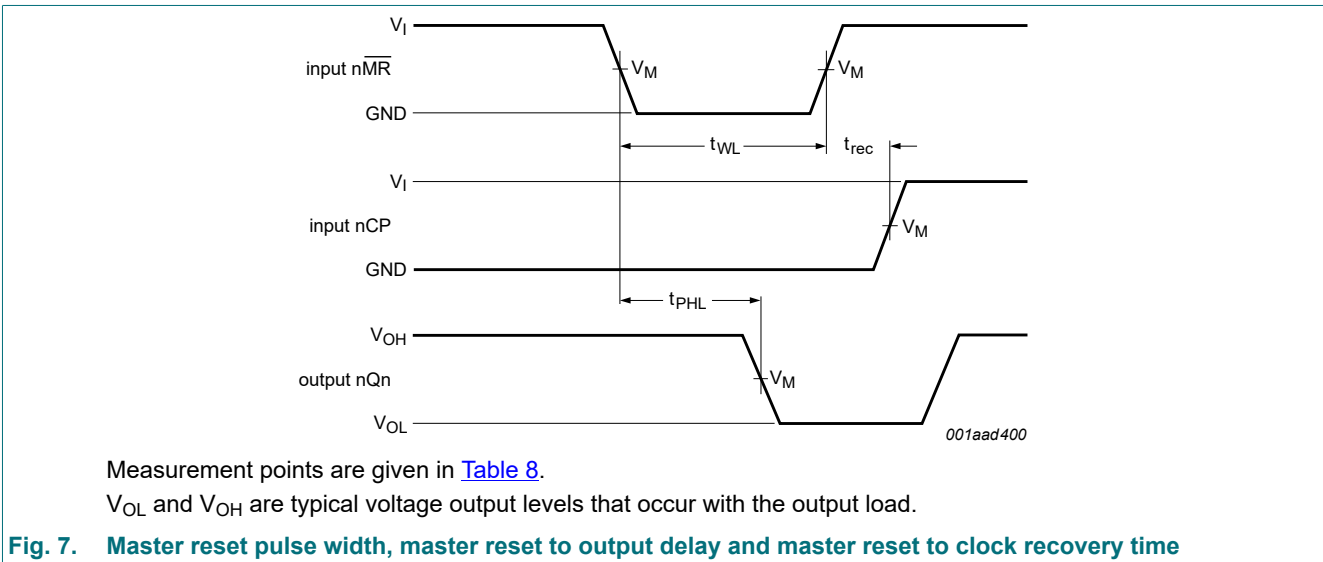
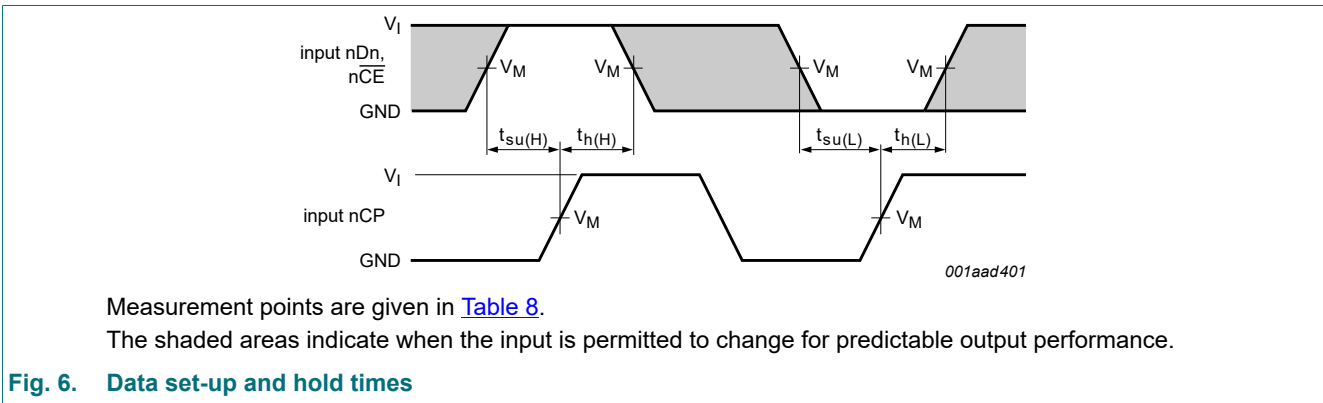
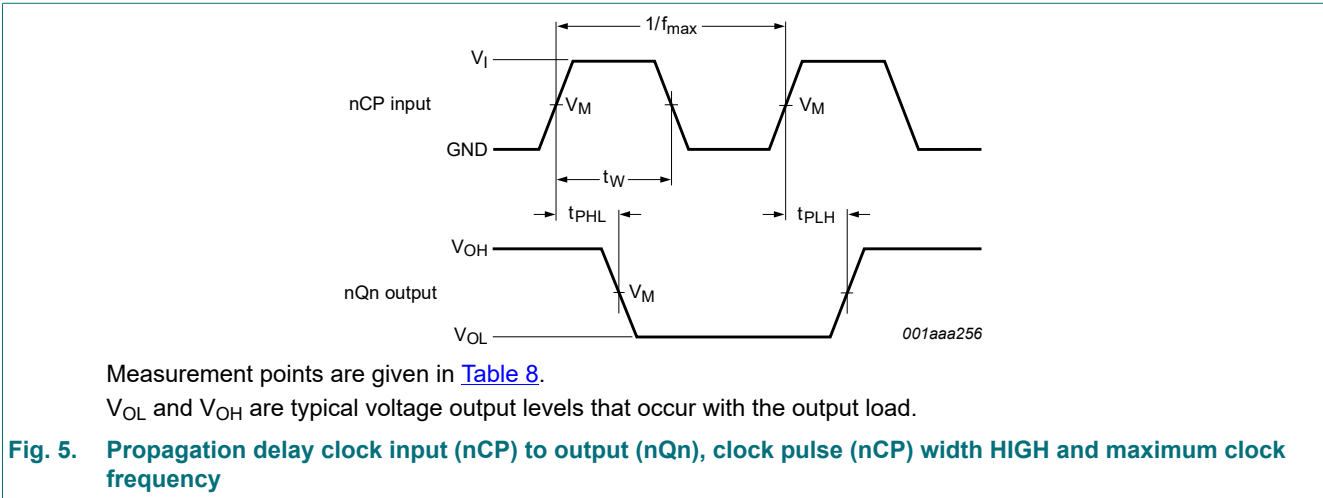


## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

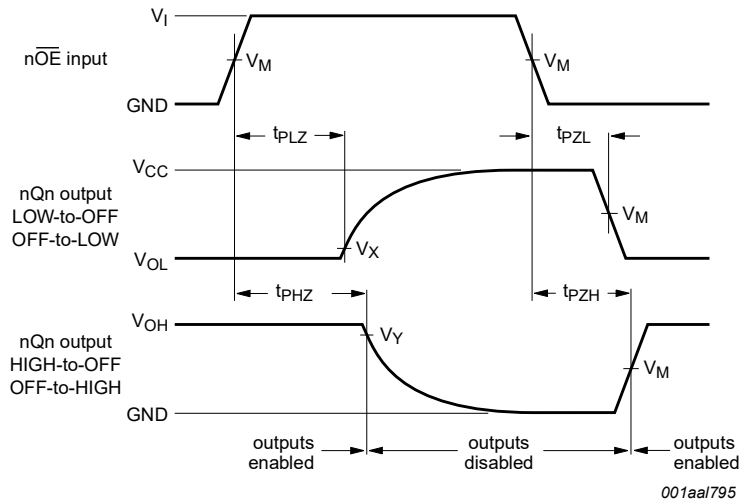
Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
t <sub>WH</sub>	pulse width HIGH	nCP; see Fig. 5	2.0	0.8	-	ns
t <sub>WL</sub>	pulse width LOW	nCP	3.0	2.1	-	ns
		nMR; see Fig. 7	2.0	0.8	-	ns
t <sub>rec</sub>	recovery time	nMR to nCP; see Fig. 7	2.0	1.3	-	ns
f <sub>max</sub>	maximum frequency	CP; see Fig. 5	150	-	-	MHz
<b>V<sub>CC</sub> = 3.3 V ± 0.3 V</b>						
t <sub>PLH</sub>	LOW to HIGH propagation delay	nCP to nQn; see Fig. 5	1.0	2.3	3.1	ns
t <sub>PHL</sub>	HIGH-to-LOW propagation delay	nCP to nQn; see Fig. 5	1.0	2.1	2.9	ns
		nMR to nQn; see Fig. 7	1.0	2.3	2.9	ns
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	nOE to nQn; see Fig. 8	1.7	2.7	4.0	ns
t <sub>PZL</sub>	OFF-state to LOW propagation delay	nOE to nQn; see Fig. 8	1.4	2.3	3.5	ns
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	nOE to nQn; see Fig. 8	2.2	3.1	4.0	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	nOE to nQn; see Fig. 8	1.8	2.6	3.5	ns
t <sub>su(H)</sub>	set-up time HIGH	nDn to nCP; see Fig. 6	1.0	0.5	-	ns
		nCE to nCP; see Fig. 6	1.0	0.1	-	ns
t <sub>su(L)</sub>	set-up time LOW	nDn to nCP; see Fig. 6	1.6	1.1	-	ns
		nCE to nCP; see Fig. 6	0.5	-0.5	-	ns
t <sub>h(H)</sub>	hold time HIGH	nDn to nCP; see Fig. 6	0.1	-0.7	-	ns
		nCE to nCP; see Fig. 6	1.0	0.5	-	ns
t <sub>h(L)</sub>	hold time LOW	nDn to nCP; see Fig. 6	0.1	-0.5	-	ns
		nCE to nCP; see Fig. 6	1.0	-0.1	-	ns
t <sub>WH</sub>	pulse width HIGH	nCP; see Fig. 5	1.5	0.7	-	ns
t <sub>WL</sub>	pulse width LOW	nCP	2.5	1.4	-	ns
		nMR; see Fig. 7	2.0	1.5	-	ns
t <sub>rec</sub>	recovery time	nMR to nCP; see Fig. 7	2.0	1.1	-	ns
f <sub>max</sub>	maximum frequency	CP; see Fig. 5	250	-	-	MHz

- [1] All typical values for V<sub>CC</sub> = 2.5 V ± 0.2 V are measured at V<sub>CC</sub> = 2.5 V and T<sub>amb</sub> = 25 °C.  
All typical values for V<sub>CC</sub> = 3.3 V ± 0.3 V are measured at V<sub>CC</sub> = 3.3 V and T<sub>amb</sub> = 25 °C.

10.1. Waveforms and test circuit



18-bit bus-interface D-type flip-flop with reset and enable; 3-state



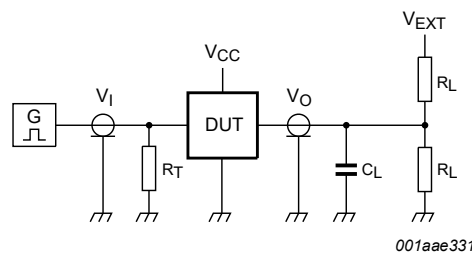
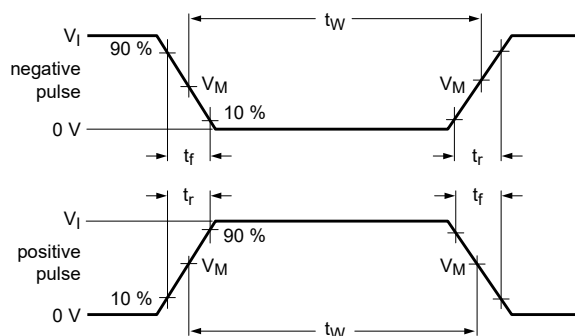
Measurement points are given in [Table 8](#).

$V_{OL}$  and  $V_{OH}$  are typical voltage output levels that occur with the output load.

**Fig. 8. OFF-state to HIGH and LOW propagation delays and LOW and HIGH to OFF-state propagation delays**

**Table 8. Measurement points**

$V_{CC}$	Input	Output		
	$V_M$	$V_M$	$V_X$	$V_Y$
$\leq 2.7\text{ V}$	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$	$V_{OL} + 0.15\text{ V}$	$V_{OH} - 0.15\text{ V}$
$\geq 3.0\text{ V}$	1.5 V	1.5 V	$V_{OL} + 0.3\text{ V}$	$V_{OH} - 0.3\text{ V}$



Test data is given in [Table 9](#).

Definitions test circuit:

$R_L$  = Load resistance.

$C_L$  = Load capacitance including jig and probe capacitance.

$R_T$  = Termination resistance should be equal to output impedance  $Z_o$  of the pulse generator.

$V_{EXT}$  = Test voltage for switching times.

**Fig. 9. Test circuit for measuring switching times**

Table 9. Test data

Input				Load		$V_{EXT}$		
$V_I$	$f_i$	$t_w$	$t_r, t_f$	$C_L$	$R_L$	$t_{PHZ}, t_{PZH}$	$t_{PLZ}, t_{PZL}$	$t_{PLH}, t_{PHL}$
3.0 V or $V_{CC}$ whichever is less	$\leq 10$ MHz	500 ns	$\leq 2.5$ ns	50 pF	500 $\Omega$	GND	6 V or $V_{CC} \times 2$	open

11. Package outline

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1 mm

SOT364-1

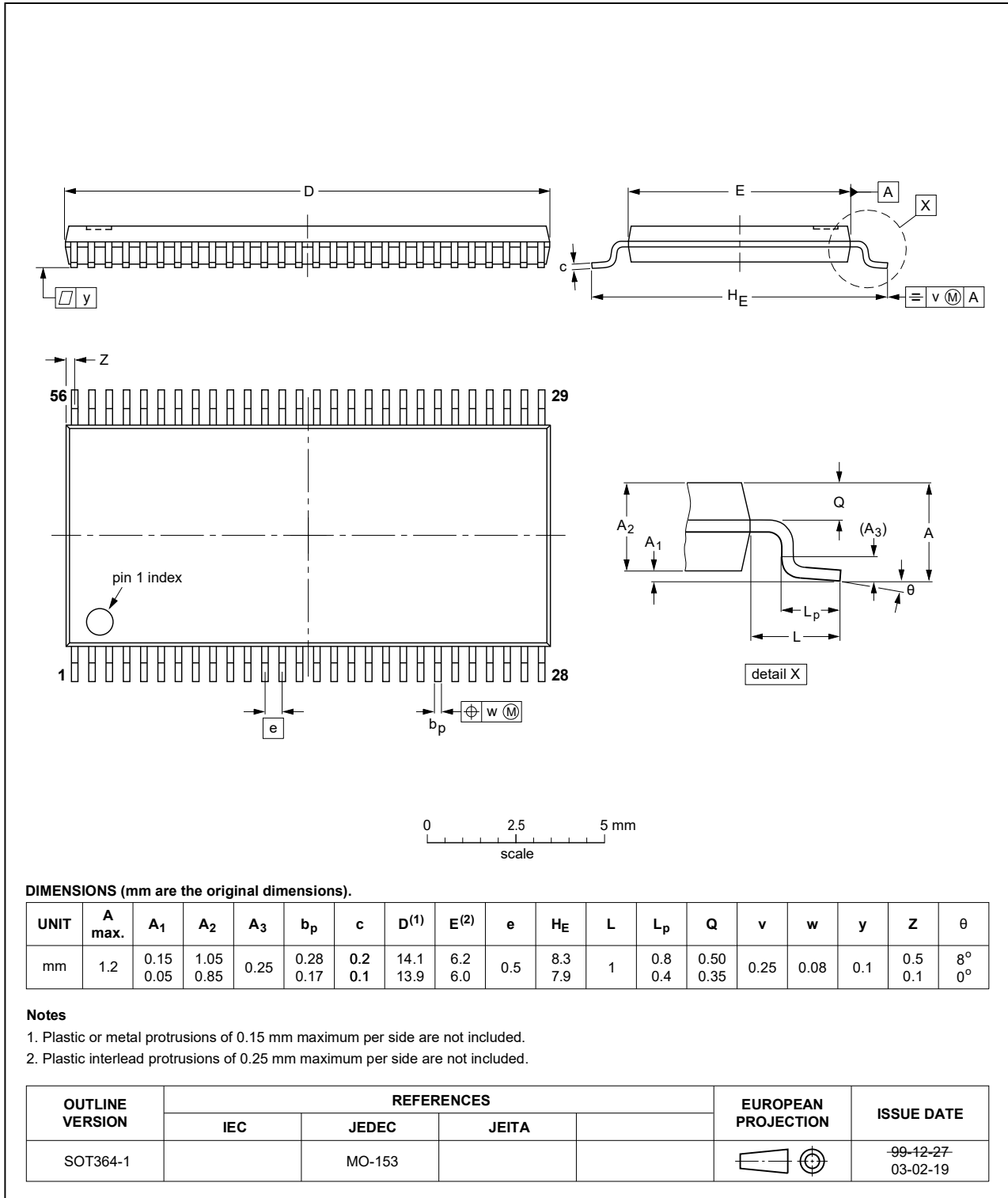


Fig. 10. Package outline SOT364-1 (TSSOP56)

## 12. Abbreviations

Table 10. Abbreviations

Acronym	Description
BiCMOS	Bipolar Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
MIL	Military
MM	Machine Model
MOS	Metal-Oxide Semiconductor
TTL	Transistor-Transistor Logic

## 13. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVT16823 v.6	20201020	Product data sheet	-	74ALVT16823 v.5
Modifications:	<ul style="list-style-type: none"> <li>Type number 74ALVT16823DL (SOT371-1 / SSOP56) removed.</li> <li><a href="#">Section 1</a> and <a href="#">Section 2</a> updated.</li> </ul>			
74ALVT16823 v.5	20180122	Product data sheet	-	74ALVT16823 v.4
Modifications:	<ul style="list-style-type: none"> <li>The format of this data sheet has been redesigned to comply with the identity guidelines of Nexperia.</li> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>			
74ALVT16823 v.4	20050802	Product data sheet	-	74ALVT16823 v.3
Modifications:	<ul style="list-style-type: none"> <li>The format of this data sheet has been redesigned to comply with the new presentation and information standard of Philips Semiconductors.</li> <li><a href="#">Section 2</a>: modified 'Jedec Std 17' into 'JESD78'</li> <li><a href="#">Section 10</a>: changed propagation delays.</li> </ul>			
74ALVT16823 v.3	19980612	Product specification	-	74ALVT16823 v.2
74ALVT16823 v.2	19980612	Product specification	-	74ALVT16823 v.1
74ALVT16823 v.1	19980303	Product specification	-	-

## 14. Legal information

### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the internet at <https://www.nexperia.com>.

### Definitions

**Draft** — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. Nexperia does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

**Short data sheet** — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local Nexperia sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

**Product specification** — The information and data provided in a Product data sheet shall define the specification of the product as agreed between Nexperia and its customer, unless Nexperia and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the Nexperia product is deemed to offer functions and qualities beyond those described in the Product data sheet.

### Disclaimers

**Limited warranty and liability** — Information in this document is believed to be accurate and reliable. However, Nexperia does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. Nexperia takes no responsibility for the content in this document if provided by an information source outside of Nexperia.

In no event shall Nexperia be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, Nexperia's aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the Terms and conditions of commercial sale of Nexperia.

**Right to make changes** — Nexperia reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

**Suitability for use** — Nexperia products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an Nexperia product can reasonably be expected to result in personal

injury, death or severe property or environmental damage. Nexperia and its suppliers accept no liability for inclusion and/or use of Nexperia products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

**Quick reference data** — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. Nexperia makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using Nexperia products, and Nexperia accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the Nexperia product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

Nexperia does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using Nexperia products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). Nexperia does not accept any liability in this respect.

**Limiting values** — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

**Terms and conditions of commercial sale** — Nexperia products are sold subject to the general terms and conditions of commercial sale, as published at <http://www.nexperia.com/profile/terms>, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. Nexperia hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of Nexperia products by customer.

**No offer to sell or license** — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

**Export control** — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

**Non-automotive qualified products** — Unless this data sheet expressly states that this specific Nexperia product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. Nexperia accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without Nexperia's warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond Nexperia's specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies Nexperia for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond Nexperia's standard warranty and Nexperia's product specifications.

**Translations** — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

### Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

## Contents

---

<b>1. General description</b> .....	<b>1</b>
<b>2. Features and benefits</b> .....	<b>1</b>
<b>3. Ordering information</b> .....	<b>1</b>
<b>4. Functional diagram</b> .....	<b>2</b>
<b>5. Pinning information</b> .....	<b>4</b>
5.1. Pinning.....	4
5.2. Pin description.....	4
<b>6. Functional description</b> .....	<b>5</b>
<b>7. Limiting values</b> .....	<b>5</b>
<b>8. Recommended operating conditions</b> .....	<b>5</b>
<b>9. Static characteristics</b> .....	<b>6</b>
<b>10. Dynamic characteristics</b> .....	<b>8</b>
10.1. Waveforms and test circuit.....	10
<b>11. Package outline</b> .....	<b>13</b>
<b>12. Abbreviations</b> .....	<b>14</b>
<b>13. Revision history</b> .....	<b>14</b>
<b>14. Legal information</b> .....	<b>15</b>

---

© Nexperia B.V. 2020. All rights reserved

For more information, please visit: <http://www.nexperia.com>

For sales office addresses, please send an email to: [salesaddresses@nexperia.com](mailto:salesaddresses@nexperia.com)

Date of release: 20 October 2020

---